

245903US-2 CONT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF: :  
SHINICH MURAKAWA, ET AL. : GROUP ART UNIT:  
SERIAL NO: NEW CONT. APPLN. :  
FILED: HEREWITH : EXAMINER:  
FOR: APPARATUS AND METHOD :  
FOR TESTING ELECTRODE  
STRUCTURE FOR THIN DISPLAY...

PRELIMINARY AMENDMENT

COMMISSIONER FOR PATENTS  
Alexandria, Virginia 22313

SIR:

Prior to initial examination on the merits, please amend the above-identified  
application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Remarks/Arguments** begin on page 3 of this paper.